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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**Sheet 1 of 1

Application #	10/520,656
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First Inventor	BOSSI
Art Unit	1743
Examiner	
Docket #	P08538US00/MP

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NON PATENT LITERATURE DOCUMENTS

Exam. Initial*	Include NAME of the author (in CAPS), Title of Article/Item, Date, Page(s), Volume-Issue No., Publisher, City and/or Country where published	Trans-lation
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/D.K./	Manz et al., <i>Adv. In Chromatog.</i> (1993), 33, 1-66	

Examiner Signature	/Dean Kwak/	Date Considered	01/07/2009
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* Examiner: Initial if considered, whether or not citation is in conformance with MPEP §609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.